	Search Notes	
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I	JNDIER JIETT ENJER EITHD RIEFD TINNE OTSJO JINSO	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/532,529	DUNKEL ET AL.	
Examiner	Art Unit	
Karen Cheng	1626	

	SEARCHED				
Class	Subclass	Date	Examiner		
548	181	12/8/2006	кс		
548	200	12/8/2006	КС		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
STN Structure Search (see attached)	12/7/2006	КС
EAST Search (see attached)	12/8/2006	кс
Inventor Name Search	12/6/2006	кс